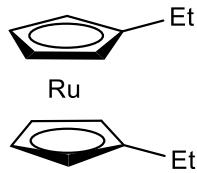


Catalog # 44-0040 Bis(ethylcyclopentadienyl)ruthenium(II), 98% (99.9%-Ru)



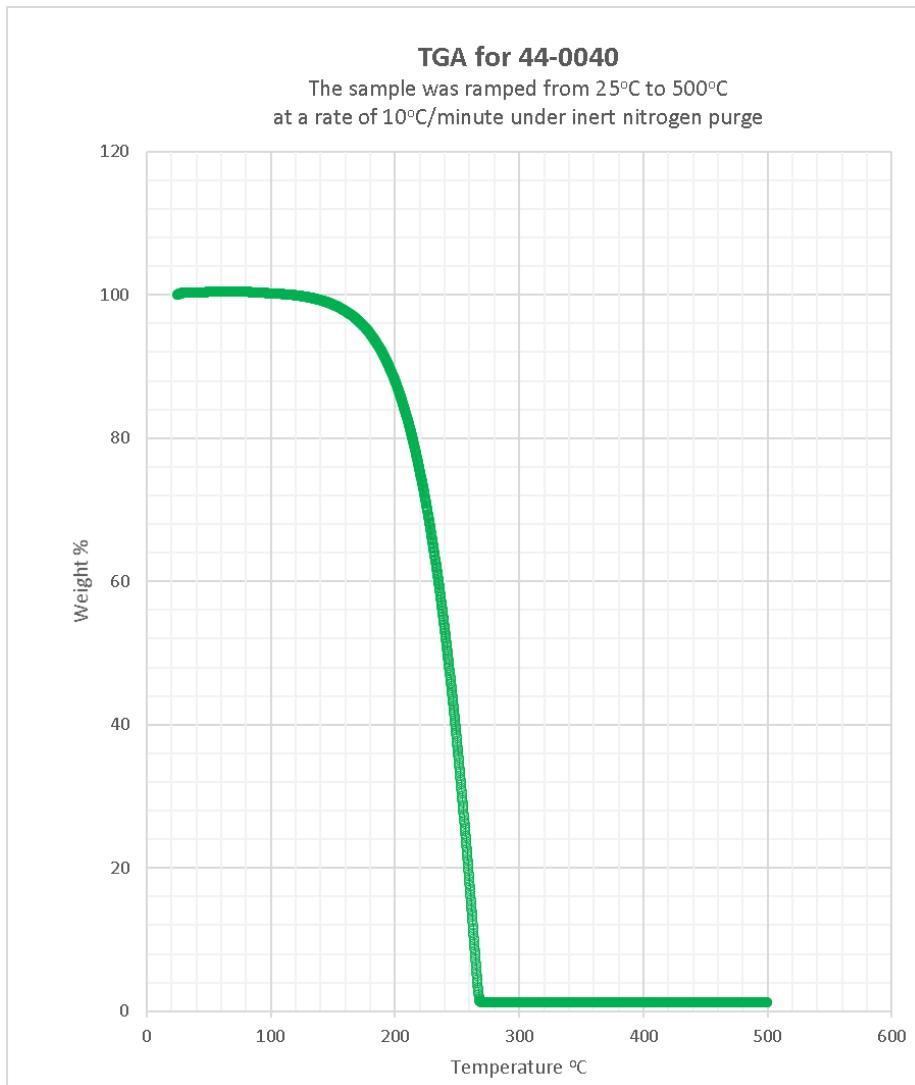
#### Thermal Behavior:

- Vapor pressure: 0.18 Torr at 80 °C [1]
- TGA available in [3]
- Melting point: 6 °C [7]
- Decomposition temperature: 350 °C [7]

#### Technical Notes:

1. Liquid Ru precursor with high thermal stability for ALD and CVD of ruthenium metal, oxide and tertiary nitride thin films.

Target Deposit	Deposition Technique	Delivery Temperature	Pressure	Co-reactants	Deposition Temperature	Ref.
Ru	ALD	80 °C	1-2 Torr	O <sub>2</sub>	270 °C	[5]
Ru	ALD	80 °C	1 Torr	O <sub>2</sub> and H <sub>2</sub>	150-200 °C	[10]
Ru	CVD	115-120 °C	0.02-0.3 Torr	O <sub>2</sub>	300-500 °C	[2, 3]
Ru	PEALD	80 °C	3 Torr	NH <sub>3</sub> plasma	270 °C	[1]
Ru	PEALD	50 °C	3.5 Torr	N <sub>2</sub> /NH <sub>3</sub> or N <sub>2</sub> /H <sub>2</sub> plasma	330 °C	[9]
RuO <sub>2</sub>	ALD	80 °C	3-5 Torr	O <sub>2</sub>	270 °C	[5]
RuO <sub>2</sub>	CVD	115 °C	0.3 Torr	O <sub>2</sub>	480 °C	[2]
RuTi <sub>x</sub> N <sub>y</sub>	PEALD	80 °C	3 Torr	Ti(NMe <sub>2</sub> ) <sub>4</sub> , N <sub>2</sub> and H <sub>2</sub> plasma	200 °C	[4]
RuTa <sub>x</sub> N <sub>y</sub>	PEALD	80 °C	3 Torr	Ta(NMe <sub>2</sub> ) <sub>3</sub> (NC <sub>5</sub> H <sub>11</sub> ), N <sub>2</sub> and H <sub>2</sub> plasma	230 °C	[6]
RuAl <sub>x</sub> N <sub>y</sub>	PEALD	80 °C	3 Torr	Me <sub>3</sub> Al, NH <sub>3</sub> plasma	300 °C	[8]



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